

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Yuichi SHIBAZAKI

Application No.: 10/588,029

Filed: August 1, 2006

Docket No.: 127874

For: STAGE DRIVE METHOD AND STAGE UNIT, EXPOSURE APPARATUS, AND
DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

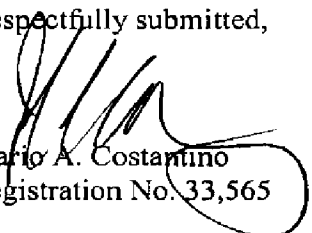
Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See Reference 186.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. A copy of the International Search Report is attached for the Examiner's information. See References 191-194.
- ☒ 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 186 and 189-208.

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- ☒ 6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 191-193 and 199.
- ☒ 7. An English language translation of one or more Patent Publication cited herein has been obtained and is attached, but has not been reviewed for accuracy. See References 186, 189, 190, 194, 197, 198 and 200-208.
- ☒ 8. Reference 184 corresponds to reference 191. Reference 187 corresponds to reference 192. Reference 188 corresponds to reference 193.

Respectfully submitted,


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Date: January 4, 2007

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127874		APPLICATION NO. 10/588,029	
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				FILING DATE August 1, 2006			

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127874		APPLICATION NO. 10/588,029	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Yuichi SHIBAZAKI			
				FILING DATE August 1, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	175.	WO 2005/106589 A1	11/10/2005	WIPO			
	176.	WO 2005/111722 A2	11/24/2005	WIPO			
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Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
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FOREIGN PATENT DOCUMENTS						
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	216.	Owa, Soichi, et al. "Update on 193nm Immersion Exposure Tool," slides 1 - 38, Immersion Workshop 2004, January 27, 2004.					
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